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Form PTO-1449 (Rev. 8-83)	U.S. Department of Commerce Patent and Trademark Office		Docket No. 740756-2406	Serial No. Not Yet Assigned	
INFORMATION DISCLOSURE STATEMENT <small>(Use several sheets if necessary)</small>					
		Applicant: Shunpei YAMAZAKI et al.			
		Filing Date: January 15, 2002		Group: 2813 2829	
U.S. PATENT DOCUMENTS					
Examiner Initial	Document Number	Date	Name	Class	Subclass
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JKR	6,124,154	09/26/2000	Miyasaka		
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FOREIGN PATENT DOCUMENTS					
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JKR	07-321339	12/08/1995	Japan		
JKR	07-130652	05/19/1995	Japan		
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OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, Etc.)					
JKR	R. Shimokawa and Y. Hayashi, "Characterization of High-Efficiency Cast-Si Solar Cell Wafers by MBIC Measurement", Japanese Journal of Applied Physics, Vol. 27, No. 5, May, 1988, pp. 751-758				
Examiner	Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.		Date Considered 1/15/02		